## Notice of References Cited Application/Control No. Applicant(s)/Patent Under Reexamination DEERMAN ET AL. Examiner Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,778,538 B2	08-2004	Landaveri et al.	370/397
*	В	US-2003/0147408 A1	08-2003	Datta et al.	370/401
*	С	US-2003/0145108 A1	07-2003	Joseph et al.	709/239
*	D	US-2005/0027862 A1	02-2005	Nguyen et al.	709/225
*	Е	US-6,901,047 B1	05-2005	Griffith et al.	370/220
*	F	US-7,092,354 B2	08-2006	Jensen, Kell Michael	370/218
*	G	US-6,081,511 A	06-2000	Carr et al.	370/256
*	Н	US-6,940,810 B1	09-2005	Roa-Diaz, Marlon B.	370/217
*	1	US-6,392,990 B1	05-2002	Tosey et al.	370/218
	J	US-			
	К	US-			
	٦	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					,
	α					
	R					
	S					
	Т			-1:		

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	V	
	w	
	x	

<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.